

Integrated Packaging Technologies for High-Performance Computing Systems: Challenges and Opportunities

Max Min

Package and SI/PI Architect

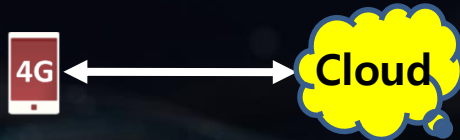
March 5, 2020

IMAPS Keynote, Samsung Foundry

Contents

- Big Data
- Toward “Beyond Moore’s Law”
 - Handy Memories
 - Nearby Decaps
 - Challenges
- Summary

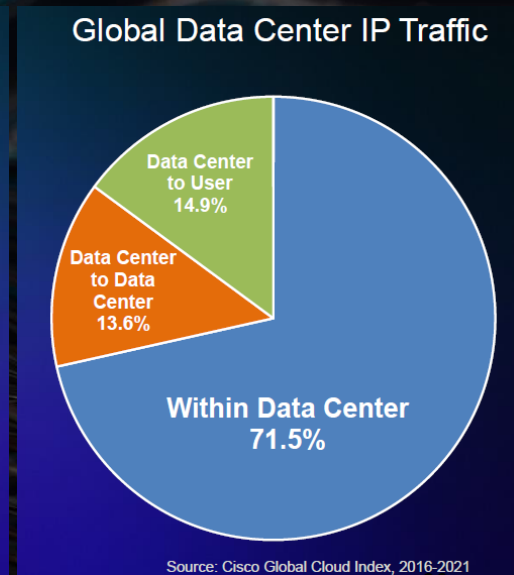
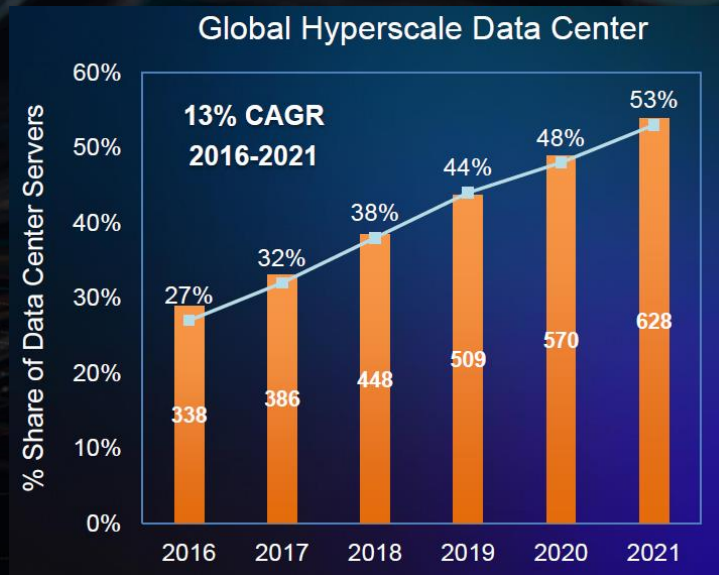
Increasing Demands on the Clouds



Regional data centers and content delivery networks, both of which brought internet infrastructure closer to the users.



Deploying infrastructure needs to **go beyond regional deployment and operation**, and also be deployed more locally.



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Q: Big Data! What we need?

A: Technologies for big data **processing**!

Let machine



Kakao Talk (messenger) "Busy" Emoticon

do the work with **AI**!

- Toward “Beyond Moore’s Law”

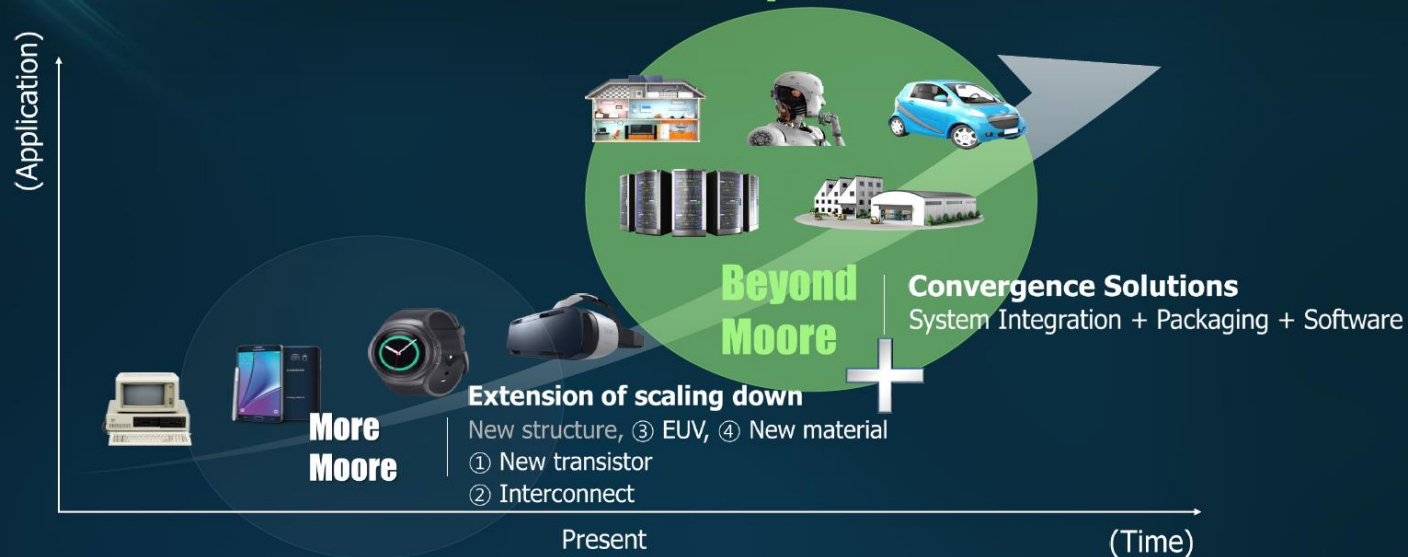
"Beyond Moore's Law"

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Technology Paradigm Shift to "Beyond Moore"

Driving variety of innovations beyond simple down-scaling to extend Moore's law

More Moore → **Beyond Moore**

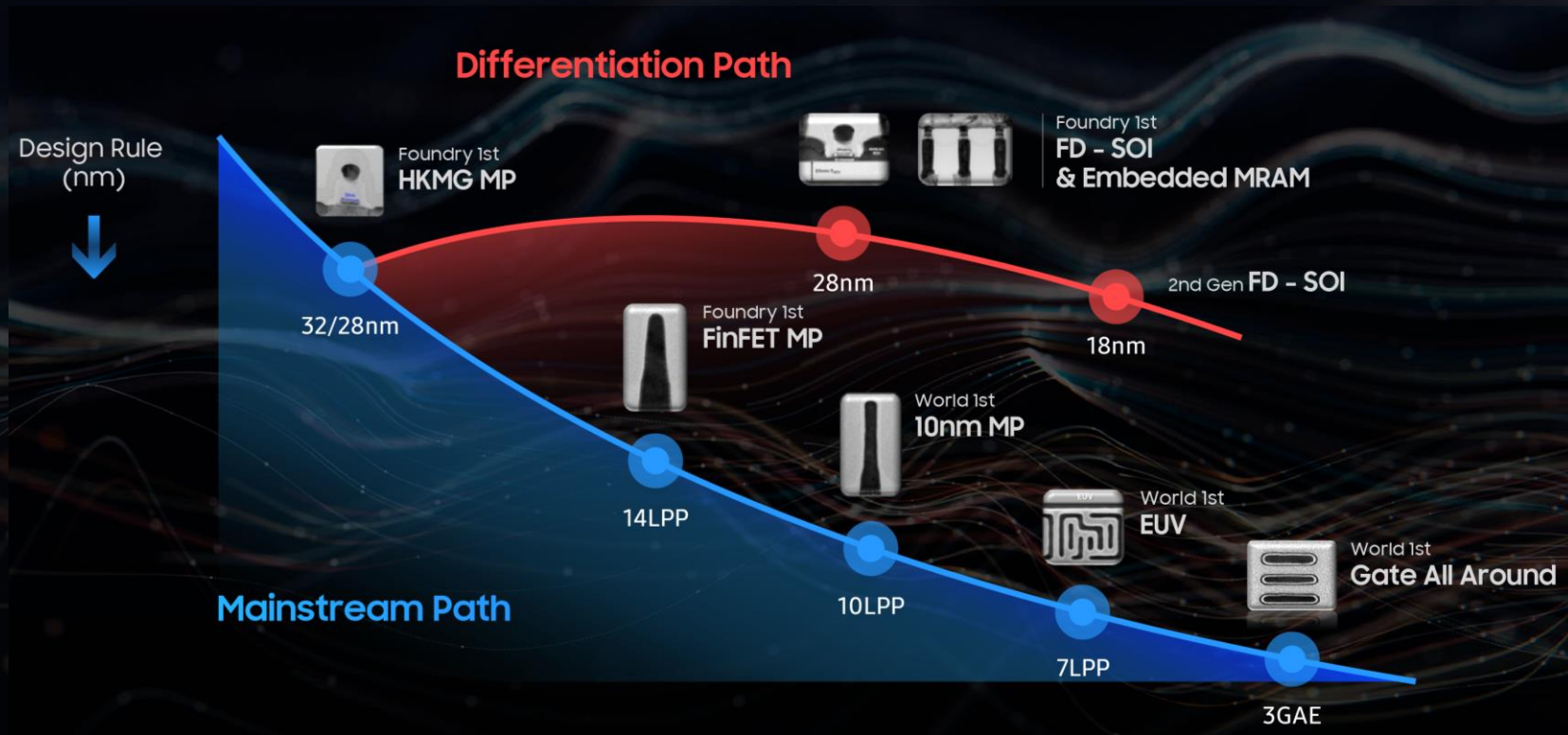


※ Moore's Law : Number of transistors doubles in 18 month period

Source: 2018 IEDM Keynote presented by ES Jung (President of Samsung Foundry)

Silicon Technologies for More Moore

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Samsung Foundry, Long History of Proven Silicon Technology

- Toward “Beyond Moore’s Law”
 - **Handy memories** by Advanced Package Solutions

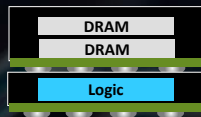
Handy Memories on X

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DDR

On board



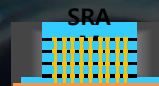
LPDDR

On package



HBM

On interposer



SRAM

On silicon

Mobile

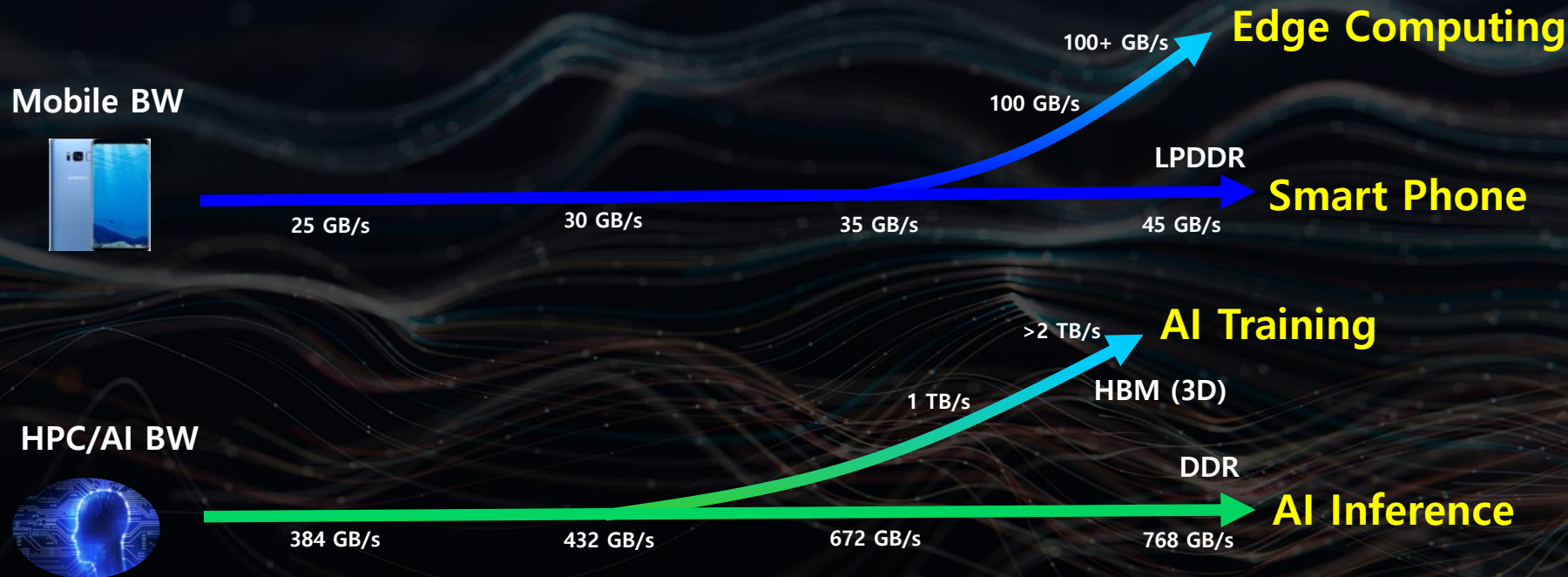
PoP/SIP/Fanout Technologies

HPC/AI

2.5D/3D/Chiplet Technologies

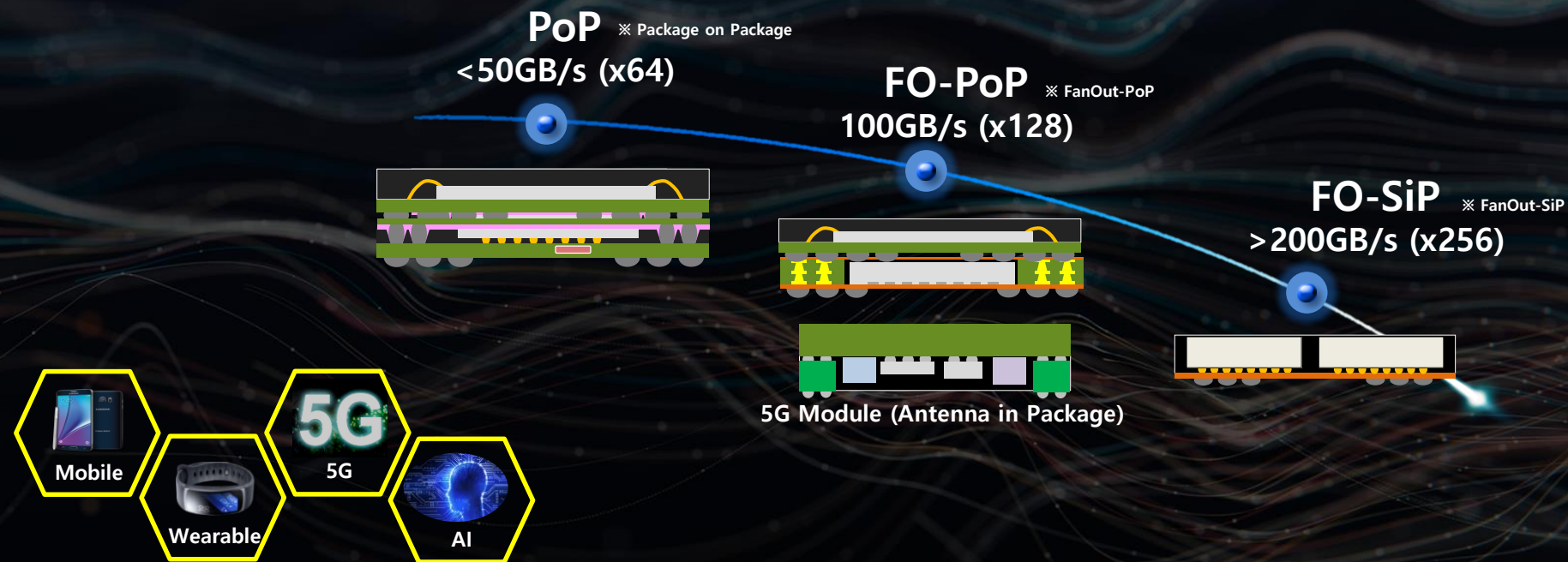
Memory integration near the logic innovates the packaging technology

System Memory Bandwidth Trend



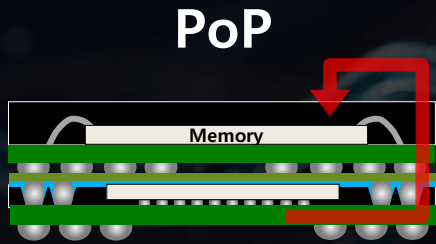
Memory bandwidth drives package platforms

PoP/Fanout/SiP Packages : LPDDR

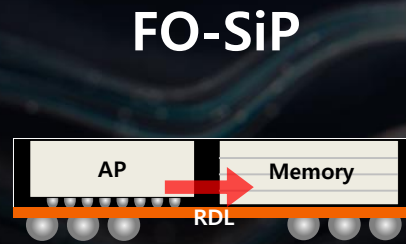


FO-SiP with Extreme Bandwidth

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VS



Thickness

Up to
↓ **40%**
vs PoP

Thermal
Resistance

Up to
↓ **40%**
vs PoP

Eye Opening
(@8Gbps)

Up to
↑ **400%**
vs PoP

Memory
Bandwidth

Up to
↑ **400%**
vs PoP

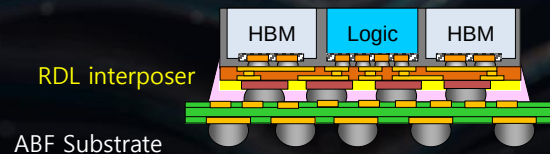
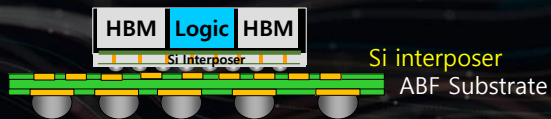
Ultimate performance, but area penalty and new memory requirement

2.5D Packages : HBM

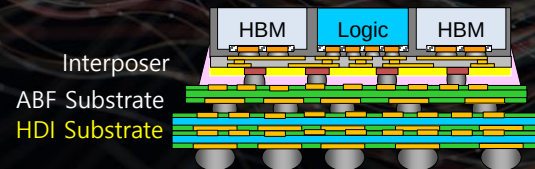
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I-Cube
High Performance



R-Cube
+ Cost Effective

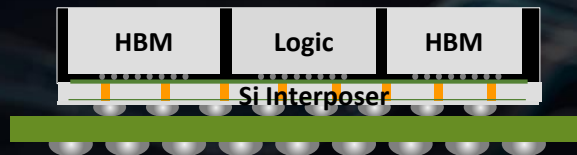


H-Cube
+ Cost Effective

2.5D I-Cube and R-Cube

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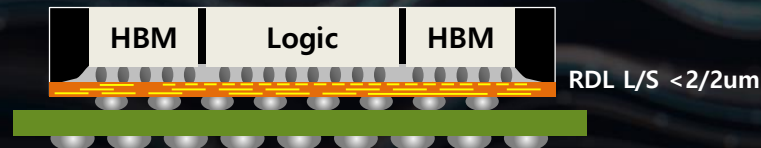
2.5D I-Cube



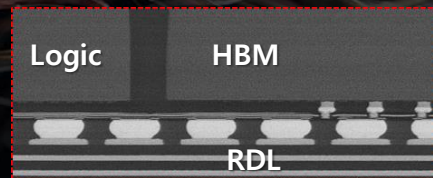
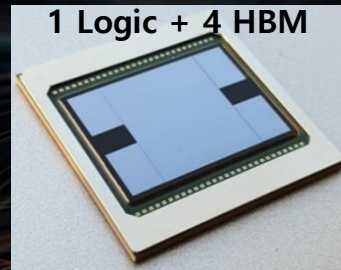
2 Logic + 8 HBM



2.5D R-Cube

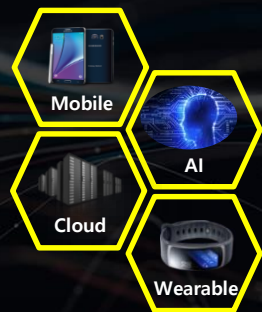


1 Logic + 4 HBM

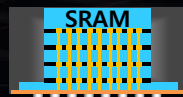
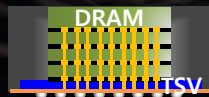


8HBM can be integrated into a 85x85mm² MIoS package

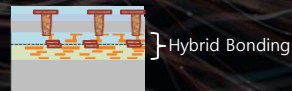
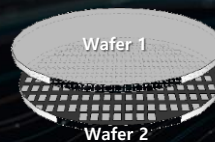
3D Packages



✓ CoW (Chip on Wafer)



✓ W2W (Wafer to Wafer)

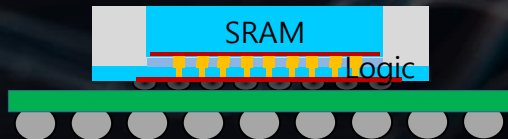


✓ D2W (Die to Wafer)



3D SRAM Package Qualified

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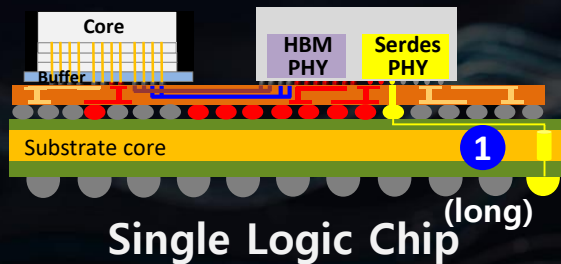


Test item	Conditions	Result
Pre-con	MSL3, 192h	Pass
TC(B)	-55~125°C, 300cyc	Pass
	-55~125°C, 700cyc	Pass
	-55~125°C, 1kcyc	Pass
uHAST	130°C/85%RH, 96h	Pass
	130°C/85%RH, 168h	Pass
HTS	Ta = 150°C, 500h	Pass
	Ta = 150°C, 1000h	Pass

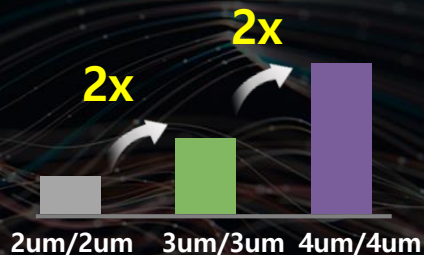
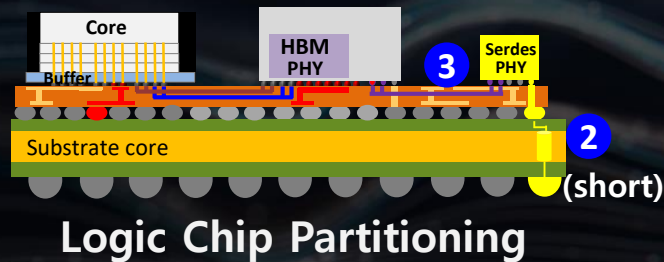
3D SRAM package was qualified

Chiplet Packages

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VS

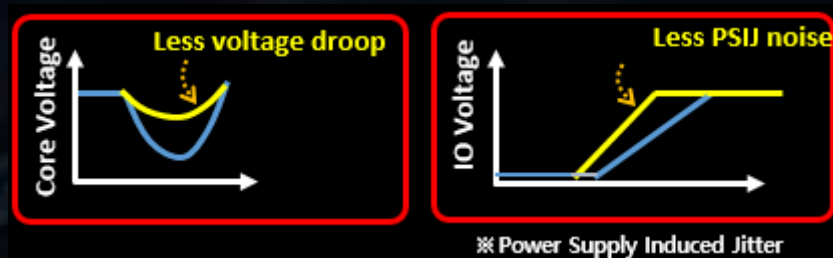


3 Allowable Max Speed

Serdes chiplet allows shorter signal length

- Toward “Beyond Moore’s Law”
 - **Nearby Decaps** by Advanced Decoupling Capacitors

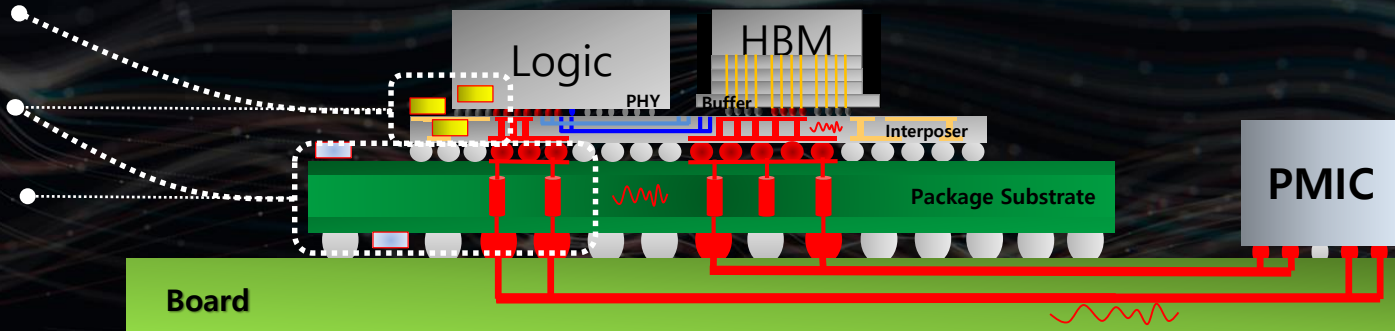
Nearby Decaps on X



✓ MIM (Metal Insulator Metal)

✓ ISC (Integrated Stacked Capacitor)

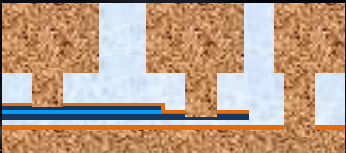
✓ EPS (Embedded Passive Substrate)

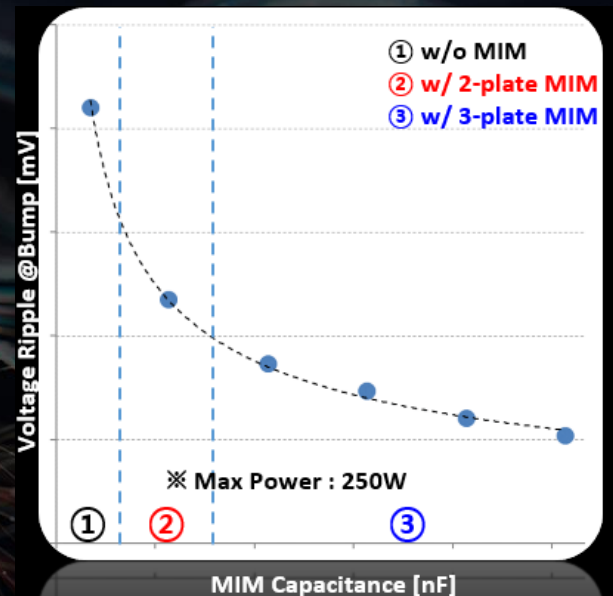


Decoupling capacitor integration near the transistor reduces the noise

MIM (Metal Insulator Metal)

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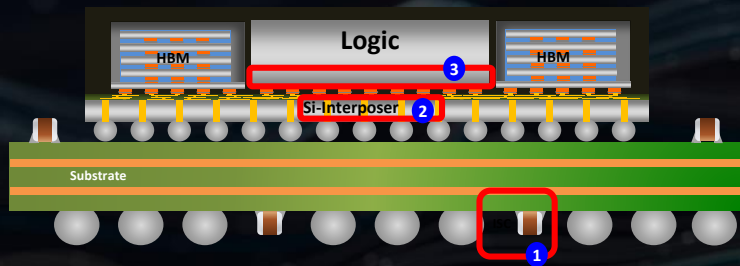
	2-plate MIM	3-plate MIM
Structure (Concept)		
MIM Capacitance	20nF/mm ²	40nF/mm ²
Position	On-chip & Si-interposer	On-chip & Si-interposer



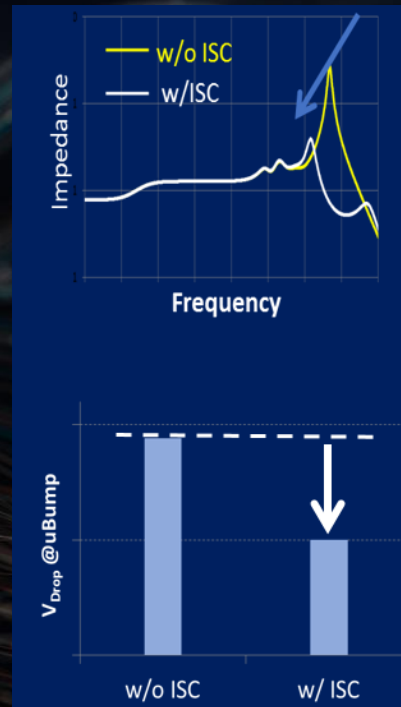
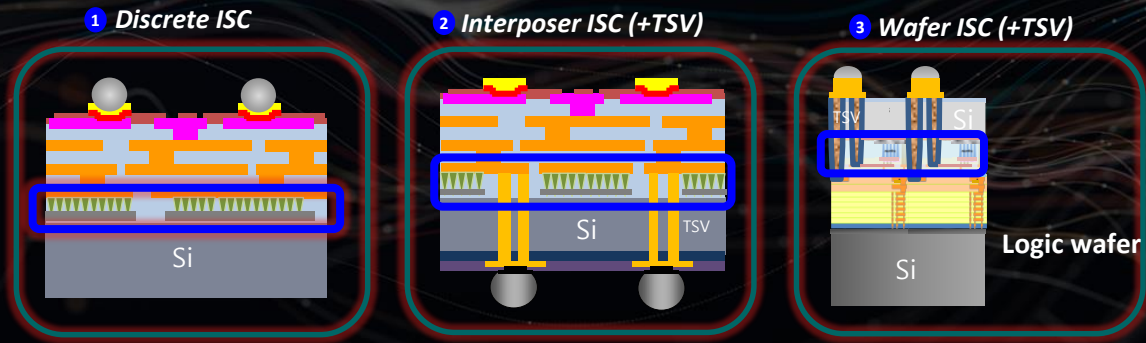
MIM provides high-frequency electrons

ISC (Integrated Stacked Capacitor)

- Thin, light and high capacitance (300nF/mm²)

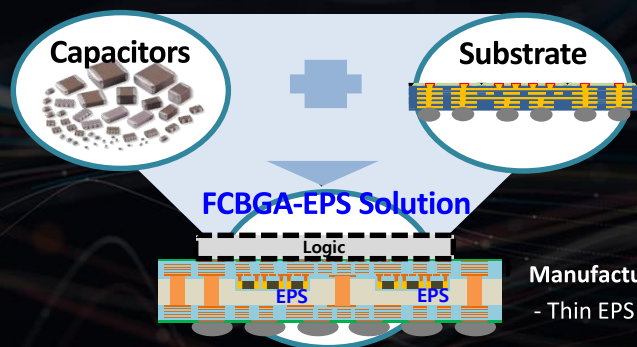


- 3 ISC types

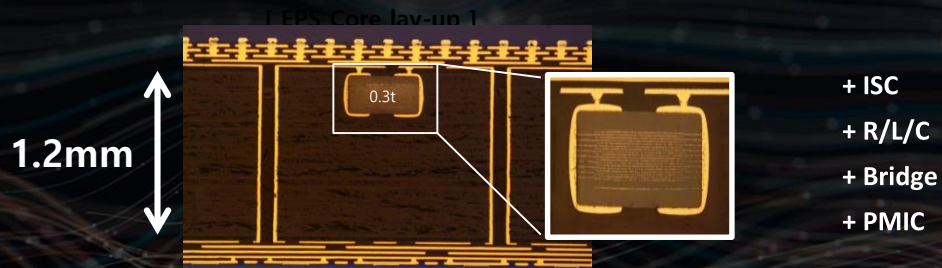


ISC provides mid/high-frequency electrons

EPS (Embedded Passive Substrate)



Manufacturability
- Thin EPS shipped since 2012



EPS provides mid/low-frequency electrons

- Toward “Beyond Moore’s Law”
 - **Challenges** : Electrical, Thermal, Mechanical

Electrical Challenges

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2 Crosstalk Noise



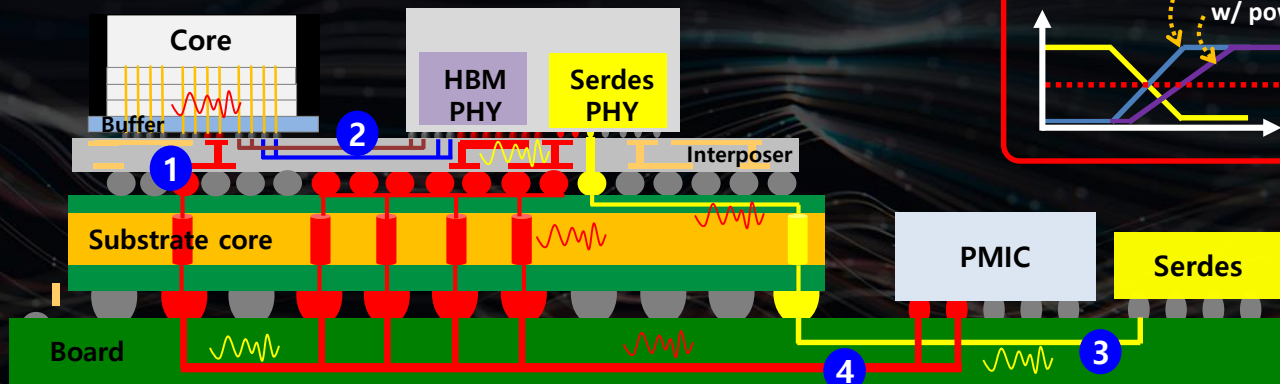
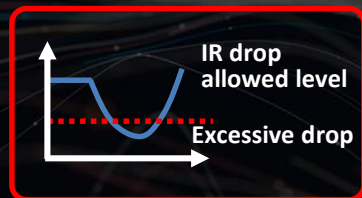
3 Signal Degradation



4 Power Supply Induced Voltage Noise (PSIJ)



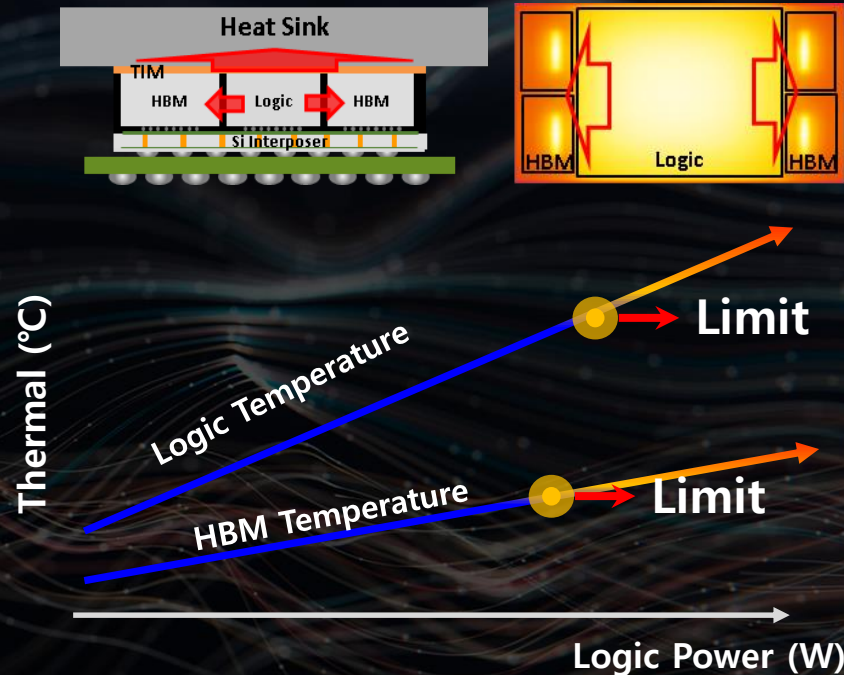
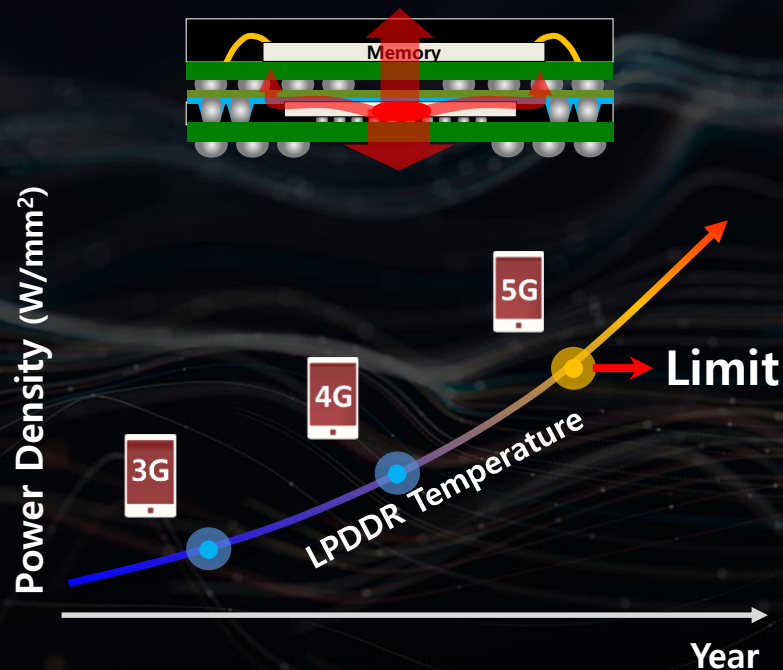
1 IR Drop



Early SI/PI feasibility, SI/PI-aware signoff & Function validation

Thermal Challenges

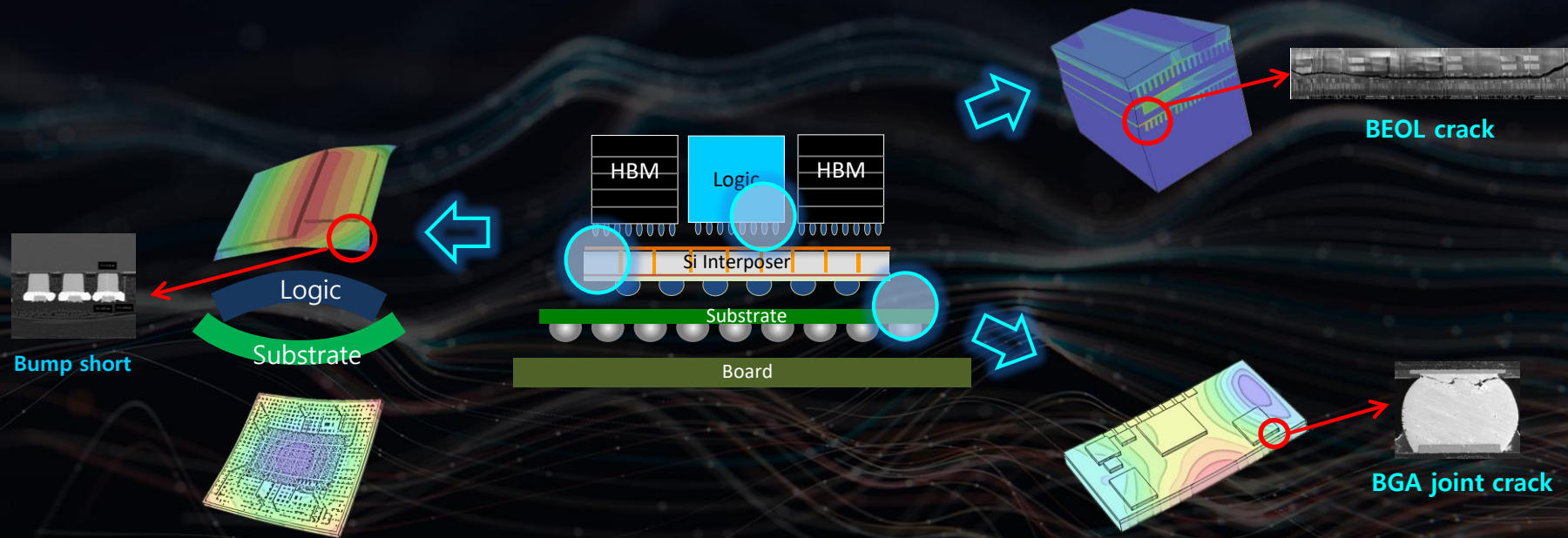
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Early thermal feasibility & TTV validation

Mechanical Challenges

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Early mechanical feasibility & MTV, CPI, BLR validation

For Big Data Era, the HPC/AI system needs

- ❖ **Handy Memories** by Advanced Package Solutions
- ❖ **Nearby Decaps** by Advanced Decoupling Capacitors
- ❖ **Early SI/PI/Thermal/Mechanical Feasibility & Validation**